## Notice of References Cited Application/Control No. 10/667,773 Applicant(s)/Patent Under Reexamination OKAWA ET AL. Examiner Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,321,501	06-1994	Swanson et al.	356/479
*	В	US-6,724,418	04-2004	Takahashi, Tadashi	348/65
*	C	US-6,594,036	07-2003	Wong et al.	358/471
*	D	US-2002/0196334	12-2002	Saito et al.	348/65
*	E	US-6,141,577	10-2000	Rolland et al.	600/407
*	F	US-6,999,608	02-2006	Toida, Masahiro	382/131
*	O	US-5,508,805	04-1996	Muranishi et al.	356/493
*	Ι	US-6,608,684	08-2003	Gelikonov et al.	356/479
*	ı	US-5,459,570	10-1995	Swanson et al.	356/479
*	J	US-6,501,551	12-2002	Tearney et al.	356/477
*	К	US-6,809,866	10-2004	Xie et al.	359/618
*	L	US-6,615,072	09-2003	Izatt et al.	600/478
*	М	US-6,760,110	07-2004	Aoki et al.	356/445

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					·
	0					
3	P					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	>	
	W	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.